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APPLICANT
Colin FORNO et al.

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U.S. PATENT DOCUMENTS

[illegible]

FOREIGN PATENT DOCUMENTS

[illegible]

OTHER DOCUMENTS

OTHER DOCUMENTS (Include Name of the author (in CAPITAL LETTERS), title of the article (when appropriate), title of the item (book, magazine, journal, serial, symposium, catalog, etc.), date, page(s), volume-issue number(s), publisher, city and/or country where published)

ACH		"A new method for displaying indented and other markings on documents", C. Forno, <u>Science & Justice</u> , 35(1); 45-51, 1995.
		Extract from Speckle Metrology, Ed. 12.5, Sirohi, Marcel Deker, Inc., New York, 1993.
ACH		"Video-rate fringe analyzer based on phase-shifting electronic moire patterns", Jun-ichi Kato, et al., <u>Applied Optics</u> , pp. 8403-8406 Vol. 36, No. 32, November 10, 1997.

EXAMINER

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